Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/625,567	FUNAKOSHI ET AL.	
Examiner	Art Unit	

Nhan T. Tran

2622

SEARCHED					
Class	Subclass	Date	Examiner		
			-		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Updated EAST - previously cited references were used	9/18/2007	NT	